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Inner tracking devices at the Belle II experiment

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In the future Belle II experiment at the SuperKEKB collider in Tsukuba, Japan, charged particle tracking in the vicinity of the $e^+ e^-$ interaction point is provided by a two-layer silicon pixel detector based on the novel DEPFET technology (PXD) and by a four-layer silicon strip detector (SVD). In this presentation, we review the technology and the design of these two devices, and describe the current state of their construction.

additional information

Submitted on behalf of the Belle II collaboration. Actual presenter will be selected by the Belle II collaboration at a later time.

Author: SCHWANDA, Christoph (Austrian Academy of Sciences)

Presenter: CASAROSA, Giulia (Sezione di Pisa (IT))

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